

Notice of References Cited	Application/Control No. 09/711,504	Applicant(s)/Patent Under Reexamination KATOH ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,271,540	08-2001	Miyamoto et al	257/59
	B	US-6,285,041	04-2001	Naguchi	257/61
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 4 -14261	01-1992	Japan	Shindo et al	
	O	JP 4-181779	06-1992	Japan	Nakazawa	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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